Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
09/633,782	LEE ET AL.	
Examiner	Art Unit	
HOAN C. NGUYEN	2871	

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SEARCHED					
Class	Subclass	Date	Examiner		
349	43	9/8/2005	CHN		
257	59	9/8/2005	CHN		
257	72	9/8/2005	CHN		
345	92	9/8/2005	CHN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
east search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	9/8/2005	CHN		
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